Ei-021

Room: IC

Ex offset of the GEOTAIL Double Probe Observations(2)

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Electric field detecter using double probe technique onboard GEOTAIL produces good quality of data. However there are appearent offsets in X component of the oberved electric field. The main cause of this offset is considered as the differences of sunlit area between a pair of the probes and asymmetry of photo electron clouds around the probes. The amount of this Ex offset is not yet evaluated enough. The purpose of this paper is to evaluate the Ex offset in various regions and generate an index of the Ex offset for analysis using electric field data.

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